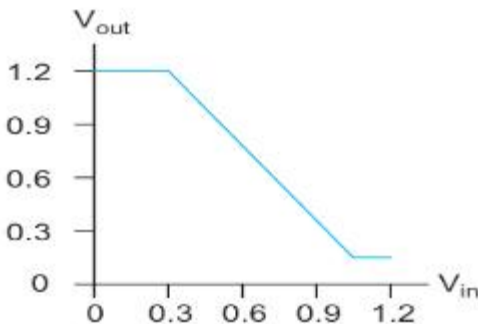


Intergrated Circuits report 1

※ 과제는 A4용지에 자필로 작성한뒤 스테이플러로 제본하여 제출해 주시기 바랍니다.

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시험 당일 중간고사 시작 전 제출

1)
Sketch a transistor-level schematic of a CMOS 3-input XOR gate. You may assume you have both true and complementary versions of the inputs available.
2)
Sketch a transistor-level schematic for a compound CMOS logic gate for each of the following functions: a) $Y = \overline{ABC + D}$ b) $Y = \overline{(AB + C)} \cdot D$ c) $Y = \overline{AB + C} \cdot (A + B)$
3)
Sketch a stick diagram for a CMOS 4-input NOR gate
4)
Consider the nMOS transistor in a $0.6 \mu\text{m}$ process with gate oxide thickness of 100 \AA . The doping level is $N_A = 2 \times 10^{17} \text{ cm}^{-3}$ and the nominal threshold voltage is 0.7 V . The body is tied to ground with a substrate contact. How much does the threshold change at room temperature if the source is at 4 V instead of 0 ?
5)
A novel inverter has the transfer characteristics shown in Figure 2.34. What are the values of V_{IL} , V_{IH} , V_{OL} , and V_{OH} that give best noise margins? What are these high and low noise margins?

FIGURE 2.34 Transfer characteristics

6)

2.21 Suppose $V_{DD} = 1.2\text{ V}$ and $V_t = 0.4\text{ V}$. Determine V_{out} in Figure 2.36 for the following. Neglect the body effect.

- a) $V_{in} = 0\text{ V}$
- b) $V_{in} = 0.6\text{ V}$
- c) $V_{in} = 0.9\text{ V}$
- d) $V_{in} = 1.2\text{ V}$.

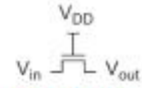


FIGURE 2.36
Single pass transistor

7)

A 90 nm long transistor has a gate oxide thickness of 16 Å. What is its gate capacitance per micron of width?

8)

Sketch a 2-input NOR gate with transistor widths chosen to achieve effective rise and fall resistances equal to a unit inverter. Compute the rising and falling propagation delays of the NOR gate driving h identical NOR gates using the Elmore delay model. Assume that every source or drain has fully contacted diffusion when making your estimate of capacitance.

9)

Estimate worst-case rising and falling delay of 3-input NAND driving h identical gates.

